Notice of References Cited Application/Control No. 10/721,598 Examiner Hanh V. Tran Applicant(s)/Patent Under Reexamination SHEN ET AL Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-	*		
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F.	US-			
	G	US-			
	Н	US-			
	ı	US-)
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	57184028	11-1982	Japan	Matsuoka et al	108/55.3
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

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